

REVISIONS

LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
A	Change to Military Drawing format. Change part number 02 package for vendor 18324. Inactivate device 01, all packages, for new design. Remove minimum values from table I ac tests. Change P _D to 787mW. Change code ident. no. to 67268.	88-01-11	M. A. Frye
B	Change P _D to 786.5 mW. Add vendor CAGE 01295. Add figure 4, switching waveforms and test circuit. Add minimum limits to electrical parameters. Correct I _{OS} . Editorial changes throughout. Change Table II to include additional tests to final electricals and group A.	89-01-06	M. A. Frye
C	Update to reflect latest changes in format and requirements. Editorial changes throughout. - les	02-02-20	Raymond Monnin
D	Change 3.5 marking paragraph to remove "5962-". Update boilerplate to MIL-PRF-38535 requirements. - CFS	05-08-17	Thomas M. Hess

Current CAGE code is 67268

The original first sheet of this drawing has been replaced.

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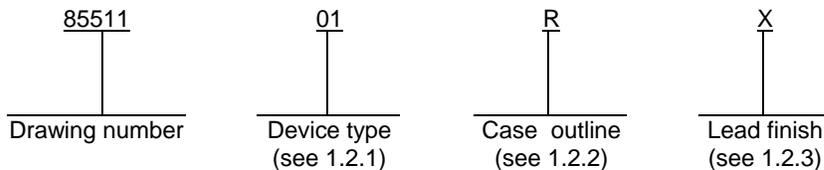
REV STATUS	REV	D	D	D	D	D	D	D	D	D	D	D	D	D	D		
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PMIC N/A	PREPARED BY Christopher A. Rauch	DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990 http://www.dsccl.dla.mil															
STANDARD MICROCIRCUIT DRAWING THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE AMSC N/A	CHECKED BY Raymond Monnin																
	APPROVED BY Michael A. Frye	MICROCIRCUIT, DIGITAL, BIPOLAR, ADVANCED SCHOTTKY, TTL, BUS TRANSCEIVERS WITH THREE-STATE OUTPUTS, MONOLITHIC SILICON															
	DRAWING APPROVAL DATE 86-02-26																
	REVISION LEVEL D	SIZE A	CAGE CODE 14933	85511													
		SHEET		1 OF 12													

1. SCOPE

1.1 Scope. This drawing describes device requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A.

1.2 Part or Identifying Number (PIN). The complete PIN is as shown in the following example:



1.2.1 Device type(s). The device type(s) identify the circuit function as follows:

<u>Device type</u>	<u>Generic number</u>	<u>Circuit function</u>
01	54F245	Octal noninverting bus transceivers, with 3-state outputs

1.2.2 Case outlines. The case outlines are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
R	GDIP1-T20 or GDIP2-T20	20	Dual-in-line
S	GDFP2-F20 or GDFP3-F20	20	Flat pack
2	CQCC1-N20	20	Square chip carrier

1.2.3 Lead finish. The lead finish is as specified in MIL-PRF-38535, appendix A.

1.3 Absolute maximum ratings.

Supply voltage	-0.5 V dc to +7.0 V dc
Input voltage range	-1.2 V dc at -18 mA to +7.0 V dc
Storage temperature range.....	-65°C to +150°C
Maximum power dissipation (P _D) per device <u>1/</u>	786.5 mW
Lead temperature (soldering, 10 seconds)	+300°C
Thermal resistance, junction-to-case (θ _{JC}).....	See MIL-STD-1835
Junction temperature (T _J)	+175°C

1.4 Recommended operating conditions.

Supply voltage range (V _{CC}).....	+4.5 V dc minimum to +5.5 V dc maximum
Minimum high level input voltage (V _{IH}).....	2.0 V dc
Maximum low level input voltage (V _{IL}).....	0.8 V dc
Case operating temperature range (T _C)	-55°C to +125°C

1/ Maximum power dissipation is defined as V_{CC} x I_{CC}. Must withstand the added P_D due to short circuit test (e.g. I_{OS}).

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990	SIZE A		85511
		REVISION LEVEL D	SHEET 2

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard Microcircuits.
 MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings.
 MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at <http://assist.daps.dla.mil/quicksearch/> or <http://assist.daps.dla.mil> or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein. Product built to this drawing that is produced by a Qualified Manufacturer Listing (QML) certified and qualified manufacturer or a manufacturer who has been granted transitional certification to MIL-PRF-38535 may be processed as QML product in accordance with the manufacturers approved program plan and qualifying activity approval in accordance with MIL-PRF-38535. This QML flow as documented in the Quality Management (QM) plan may make modifications to the requirements herein. These modifications shall not affect form, fit, or function of the device. These modifications shall not affect the PIN as described herein. A "Q" or "QML" certification mark in accordance with MIL-PRF-38535 is required to identify when the QML flow option is used.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535, appendix A and herein.

3.2.1 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.3 Truth table. The truth table shall be as specified on figure 2.

3.2.4 Logic diagram. The logic diagram shall be as specified on figure 3.

3.2.5 Test circuit and switching waveforms. The test circuit and switching waveforms shall be as specified on figure 4.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990	SIZE A		85511
		REVISION LEVEL D	SHEET 3

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full case operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-PRF-38535, appendix A. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked.

3.5.1 Certification/compliance mark. A compliance indicator "C" shall be marked on all non-JAN devices built in compliance to MIL-PRF-38535, appendix A. The compliance indicator "C" shall be replaced with a "Q" or "QML" certification mark in accordance with MIL-PRF-38535 to identify when the QML flow option is used.

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6 herein). The certificate of compliance submitted to DSCC-VA prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-PRF-38535, appendix A and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DSCC-VA shall be required for any change that affects this drawing.

3.9 Verification and review. DSCC, DSCC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990	SIZE A		85511
		REVISION LEVEL D	SHEET 4

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit	
					Min	Max		
High level output voltage, A0 through A7	V _{OH1}	V _{CC} = 4.5 V, I _{OH} = -3 mA, V _{IL} = 0.8 V, V _{IH} = 2.0 V	1, 2, 3	All	2.4		V	
High level output voltage, B0 through B7	V _{OH2}	V _{CC} = 4.5 V, I _{OH} = -12 mA, V _{IL} = 0.8 V, V _{IH} = 2.0 V	1, 2, 3	All	2.0		V	
Low level output voltage B0 through B7	V _{OL1}	V _{CC} = 4.5 V, I _{OL} = 48 mA, V _{IL} = 0.8 V, V _{IH} = 2.0 V	1, 2, 3	All		0.55	V	
Low level output voltage A0 through A7	V _{OL2}	V _{CC} = 4.5 V, I _{OL} = 20 mA, V _{IL} = 0.8 V, V _{IH} = 2.0 V	1, 2, 3	All		0.5	V	
Input clamp voltage	V _{IC}	V _{CC} = 4.5 V, I _{IH} = -18 mA, T _C = +25°C	1	All		-1.2	V	
High level input current	I _{IH1}	V _{CC} = 5.5 V, V _{IN} = 2.7 V $\overline{\text{OE}}$ and T/R only	1, 2, 3	All		40	μA	
	I _{IH2}	V _{CC} = 5.5 V, V _{IN} = 5.5 V	1, 2, 3	All		1.0	mA	
Low level input current	I _{IL}	V _{CC} = 5.5 V, V _{IN} = 0.5 V $\overline{\text{OE}}$ and T/R only	1, 2, 3	All		-1.2	mA	
Short circuit output current	I _{OS}	V _{CC} = 5.5 V, V _{OS} = 0.0 V 1/	B0 to B7	1, 2, 3	All	-100	-325	mA
			A0 to A7	1, 2, 3	All	-60	-225	mA
Low level input, off-state low output current	I _{IOZL}	V _{CC} = 5.5 V, $\overline{\text{OE}}$ = 2.0 V, V _{IOZL} = 0.5 V	1, 2, 3	All		-1.6	mA	
High level input, off-state high output current	I _{IOZH}	V _{CC} = 5.5 V, $\overline{\text{OE}}$ = 2.0 V, V _{IOZH} = 2.7 V	1, 2, 3	All		70	μA	
Supply current	I _{CCH}	V _{CC} = 5.5 V, V _{IN} = 4.5 V	1, 2, 3	All		114	mA	
	I _{CCL}	V _{CC} = 5.5 V, V _{IN} = 0.0 V	1, 2, 3	All		130	mA	
	I _{CCZ}	V _{CC} = 5.5 V, V _{IN} = 4.5 V	1, 2, 3	All		143	mA	

See footnotes at end of table.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990	SIZE A		85511
		REVISION LEVEL D	SHEET 5

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Propagation delay time, Bn to An	t _{PLH1}	V _{CC} = 5.5 V R _L = 500Ω ±5% C _L = 50 pF ±10% See figure 4	9, 10, 11	All	1.0	8	ns
	t _{PHL1}						
Propagation delay time, An to Bn	t _{PLH2}		9, 10, 11	All	1.0	8.5	ns
	t _{PHL2}						
Output disable time, \overline{OE} to An	t _{PLZ1}		9, 10, 11	All	1.2	10	ns
	t _{PZH1}						
Output disable time, \overline{OE} to Bn	t _{PLZ2}		9, 10, 11	All	1.2	10	ns
	t _{PZH2}						
Output enable time, \overline{OE} to An	t _{PZL1}	9, 10, 11	All	2.0	13	ns	
	t _{PZH1}						9, 10, 11
Output enable time, \overline{OE} to Bn	t _{PZL2}	9, 10, 11	All	2.0	13	ns	
	t _{PZH2}						9, 10, 11

1/ Not more than one output will be tested at one time and the duration of the test condition shall not exceed 1 second.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990	SIZE A		85511
		REVISION LEVEL D	SHEET 6

Device types	01	01
Case outlines	R, S	2
Terminal number	Terminal symbols	
1	T/ \bar{R}	T/ \bar{R}
2	A0	A0
3	A1	A1
4	A2	A2
5	A3	A3
6	A4	A4
7	A5	A5
8	A6	A6
9	A7	A7
10	GND	GND
11	B7	B7
12	B6	B6
13	B5	B5
14	B4	B4
15	B3	B3
16	B2	B2
17	B1	B1
18	B0	B0
19	\overline{OE}	\overline{OE}
20	V _{CC}	V _{CC}

FIGURE 1. Terminal connections.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990	SIZE A		85511
		REVISION LEVEL D	SHEET 7

Inputs		Inputs/outputs	
\overline{OE}	T/\overline{R}	An	Bn
L	L	A = B	Inputs
L	H	Inputs	B = A
H	X	(Z)	(Z)

H = High voltage level
 L = Low voltage level
 X = Don't care
 (Z) = High impedance "off" state

FIGURE 2. Truth table.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990	SIZE A		85511
		REVISION LEVEL D	SHEET 8

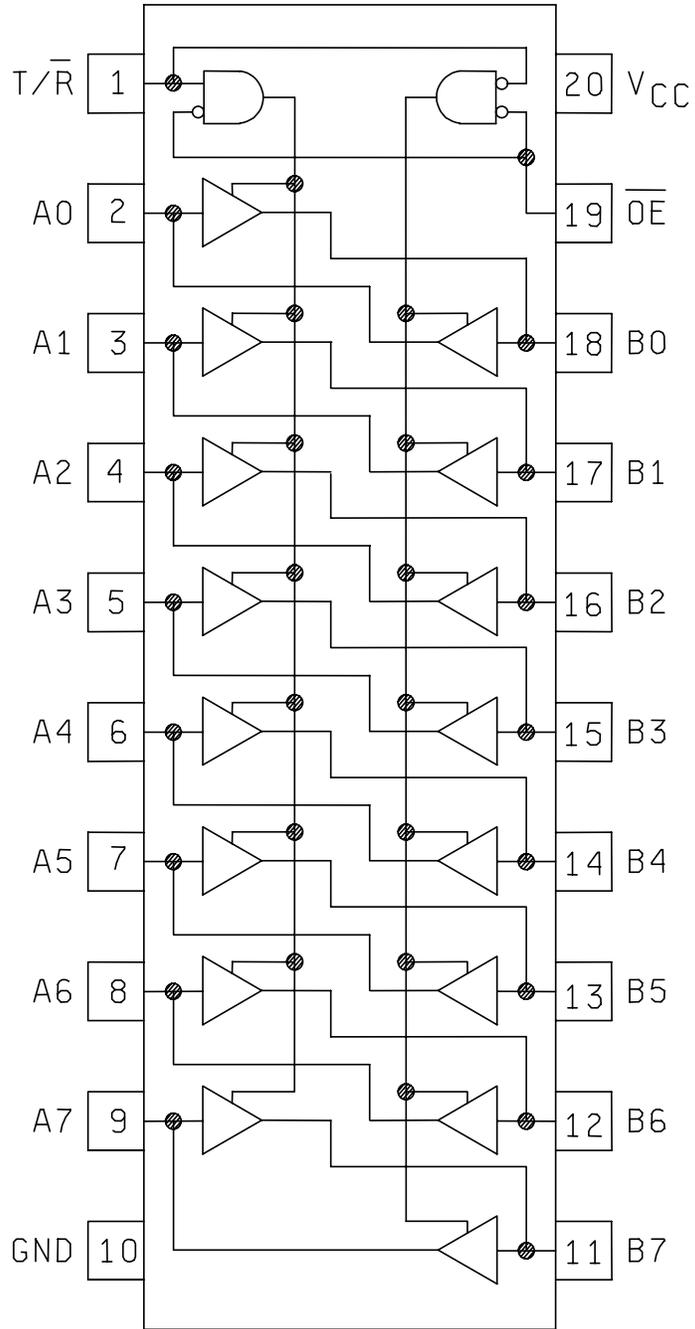
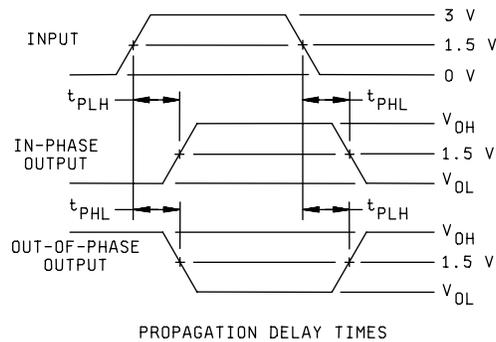
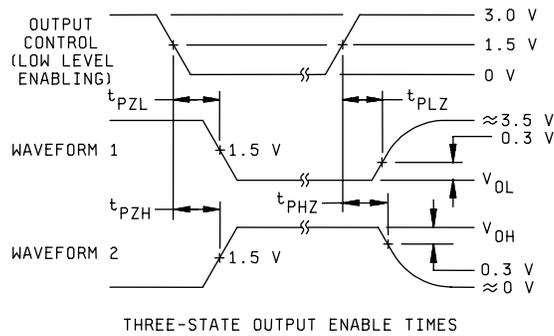
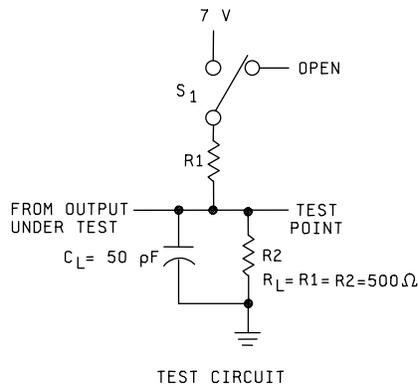


FIGURE 3. Logic diagram.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990	SIZE A		85511
		REVISION LEVEL D	SHEET 9



Notes:

1. C_L includes probe and jig capacitance.
2. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
3. All input pulses have the following characteristics; PRR = 1 MHz, $t_r = t_f = 2.5$ ns, duty cycle = 50%.
4. When measuring propagation delay times of three-state outputs, switch S1 is open.
5. The outputs are measured one at a time with one transition per measurement.
6. When measuring t_{PZL} and t_{PLZ} , switch S1 is closed.

FIGURE 4. Switching waveforms and test circuit.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990	SIZE A		85511
		REVISION LEVEL D	SHEET 10

4. VERIFICATION

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.
 - (2) $T_A = +125^{\circ}\text{C}$, minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (in accordance with MIL-STD-883, method 5005, table I)
Interim electrical parameters (method 5004)	---
Final electrical test parameters (method 5004)	1*, 2, 3, 7, 8, 9
Group A test requirements (method 5005)	1, 2, 3, 7, 8, 9, 10, 11
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

* PDA applies to subgroup 1.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroups 7 and 8 shall include verification of the truth table.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990	SIZE A		85511
		REVISION LEVEL D	SHEET 11

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.
 - (2) $T_A = +125^{\circ}\text{C}$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535, appendix A.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal.

6.4 Record of users. Military and industrial users shall inform Defense Supply Center Columbus (DSCC) when a system application requires configuration control and the applicable SMD. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0544.

6.5 Comments. Comments on this drawing should be directed to DSCC-VA, Columbus, Ohio 43218-3990, or telephone (614) 692-0547.

6.6 Approved sources of supply. Approved sources of supply are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DSCC-VA.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990	SIZE A		85511
		REVISION LEVEL D	SHEET 12

STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 05-08-17

Approved sources of supply for SMD 85511 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This information bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535. DSCC maintains an online database of all current sources of supply at <http://www.dscclia.mil/Programs/Smcr/>.

Standard microcircuit drawing PIN <u>1/</u>	Vendor CAGE number	Vendor similar PIN <u>2/</u>	Reference military specification part number
8551101RA	01295 <u>3/</u> <u>3/</u>	SNJ54F245J 54F245/BRAJC 54F245/BRA	M38510/34803BRA
8551101SA	01295 <u>3/</u> <u>3/</u>	SNJ54F245W 54F245/BSAJC 54F245/BSA	M38510/34803BSA
85511012A	01295 <u>3/</u> <u>3/</u>	SNJ54F245K 54F245M/B2AJC 54F245/B2A	M38510/34803B2A

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.
- 2/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.
- 3/ Not available from an approved source of supply.

Vendor CAGE
number

01295

Vendor name
and address

Texas Instruments, Inc.
Semiconductor Group
8505 Forest Lane
P.O. Box 660199
Dallas, TX 75243

POC: U.S. Highway 75 South
P.O. Box 84, M/S 853
Sherman, TX 75090-9493

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